PTAB Trial Practice: Insights from a Former USPTO Judge



Fitch, Even, Tabin & Flannery LLP presents a complimentary webinar, "PTAB Trial Practice: Insights from a Former USPTO Judge," featuring Fitch Even counsel and former Administrative Patent Judge Kenneth W. Hairston. The webinar will take place on Thursday, March 26, 2015, at 9 a.m. PDT / 10 a.m. MDT / 11 a.m. CDT / 12

noon EDT.

With the rise of post-issuance proceedings, an increasing number of lawyers are presenting to the Patent Trial and Appeal Board (PTAB) with little prior experience, the firm says in a realese. Moreover, the makeup of the PTAB has changed significantly in the past four years, tripling in size from about 75 judges to over 225 judges, many of whom lack substantial judicial experience. That, along with the large backlog of *ex parte* and *inter partes* cases pending before the PTAB, can greatly affect post-issuance proceedings. So what should petitioners and patent holders know as they approach a post-issuance review? And what's behind the relatively high fees in these proceedings?

During this program, Ken Hairston will share his insights on trial practice before the PTAB, addressing these topics and more:

- How to gain a judge's attention in a post-issuance proceeding
- How the backlog of PTAB cases may impact your post-issuance proceeding
- Understanding the costs involved
- How to work with PTAB trial practice rules to save time and money
- Sound, effective approaches to conducting the litigation

Ken Hairston has provided IP law counsel for nearly 40 years, including 23 years serving as an Administrative Patent Judge at the Board of Patent Appeals and Interferences (now known as the PTAB) at the U.S. Patent and Trademark Office. Drawing upon the insight gained from his judicial work, Ken currently counsels clients on complex patent prosecution matters and patent office appeals, as well as administrative post-grant patent challenges.

CLE credit has been approved for California and Illinois and is pending in Nebraska. Other states may also award CLE credit upon attendee request. There is no fee to attend, but please note registration is required.

Register for the webinar.